

FORM PTO-1449 (SUBSTITUTE)		Attorney Docket No.: MAS-FIN-193		Applic. No. 10/022,226
U.S. DEPARTMENT OF COMMERCE APR 12 2002 PATENT AND TRADEMARK OFFICE		Applicant		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))		Harry Hedler et al.		
		Filing Date December 17, 2001	Group Art Unit 2814	

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
NB	A	4,001,870	01/04/77	Saiki et al.			
NB	B	4,074,342	02/14/78	Henn et al.			
NB	C	4,366,264	12/21/82	Mukai et al.			
NB	D	4,618,878	10/21/86	Aoyama et al.			
NB	E	4,813,129	03/21/89	Karnezos			
NB	F	4,885,126	12/05/89	Pelenie			
NB	G	4,902,606	02/20/90	Patraw			
NB	H	5,072,520	12/17/91	Nelson			
NB	I	5,148,265	09/15/92	Khandros et al.			

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
	J						
	K						
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

NB	O	Anonymous: "Method of Testing Chips and Joining Chips to Substrates", XP-000169195
	P	

EXAMINER	DATE CONSIDERED
Nina Berezny	10-3-03
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
NB	A	5,148,266	09/15/92	Khandros et al.			
NB	B	5,180,311	01/19/93	Schreiber et al.			
NB	C	5,420,329	05/30/95	Zeiss			
NB	D	5,455,390	10/03/95	DiStefano et al.			
NB	E	5,477,087	12/19/95	Kawakita et al.			
NB	F	5,489,749	02/06/96	DiStefano et al.			
NB	G	5,491,302	02/13/96	DiStefano et al.			
NB	H	5,604,380	02/18/97	Nishimura et al.			
NB	I	5,619,017	04/08/97	DiStefano et al.			

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EXAMINER

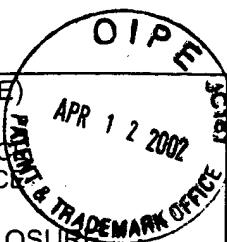
Nema Berszny

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EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
NB	A	5,666,270	09/09/97	Matsuda et al.			
NB	B	5,679,977	10/21/97	Khandros et al.			
NB	C	5,749,997	05/12/98	Tang et al.			
NB	D	5,777,379	07/07/98	Karavakis et al.			
NB	E	5,874,782	02/23/99	Palagonia			
NB	F	5,907,785	05/25/99	Palagonia			
NB	G	6,284,563 B1	09/04/01	Fjelstad			
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